

PRODUCT CHANGE NOTICE

**Wafer Fabrication Process
Improvement for the Listed Intersil
P3/PASIC Technology Products**

**Refer to:
PCN09016**

Date: March 17, 2009

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To: Our Valued Intersil Customer

Subject: **Wafer Fabrication Process Improvement for the Listed Intersil P3/PASIC Technology Products**

This notice is to inform you of a pending change in the 80V P3/PASIC EPI process used for wafer fabrication of the listed Intersil products. The changes are in the EPI process module and all qualification activities are complete.

This change will not affect the form, fit, function, or interchangeability of product. The only purpose of the change is to improve the manufacturability of the product thus guaranteeing a more consistent delivery of product from the wafer fabrication to finished goods. A summary of the qualification results is included for reference.

There will be no changes to the product design, WAT (Wafer Acceptance Test), wafer level electrical test (probe), package level electrical test, marking, or product datasheet specifications. Parts affected by this change are identifiable via Intersil's internal traceability system.

Intersil will take all necessary actions to conform to customer requirements and to ensure the continued high quality and reliability of Intersil products being supplied. Customers may expect to receive product fabricated using the improved process beginning *ninety* days from the date of this notification or upon depletion of existing inventory.

If you have previously negotiated change approval with Intersil that includes changes in wafer fabrication processing, please address this change immediately. To effectively facilitate product delivery, prompt review and approval is required.

If you have concerns with this change notice, Intersil must hear from you immediately. Please contact the nearest Intersil Sales Office or call the Intersil Corporate line at 1-888-468-3774, in the United States, or 1-321-724-7143 outside of the United States.

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PCN09016

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PCN09016 – Products Affected

HIP4080AIB	HIP4083ABZ	ISL6142CB-T	ISL6151IBZA
HIP4080AIBT	HIP4083ABZT	ISL6142CBZA	ISL6151IBZA-T
HIP4080AIBZ	HIP4083AP	ISL6142CBZA-T	ISL6152CB
HIP4080AIBZT	HIP4083APZ	ISL6142IB	ISL6152CB-T
HIP4080AIP	HIP4086AB	ISL6142IB-T	ISL6152CBZA
HIP4080AIPZ	HIP4086ABT	ISL6142IBZA	ISL6152CBZA-T
HIP4080AIY	HIP4086ABZ	ISL6142IBZA-T	ISL6152IB
HIP4081AIB	HIP4086ABZATS2490	ISL6144IR	ISL6152IB-T
HIP4081AIBT	HIP4086ABZATS2490S	ISL6144IR-T	ISL6152IBZA
HIP4081AIBTS2490S	HIP4086ABZT	ISL6144IRZA	ISL6152IBZA-T
HIP4081AIBZ	HIP4086ABZTS2490	ISL6144IRZA-T	ISL6700IB
HIP4081AIBZT	HIP4086AP	ISL6144IRZA-TS2705	ISL6700IB-T
HIP4081AIBZTS2490S	HIP4086APZ	ISL6144IV	ISL6700IBZ
HIP4081AIP	HIP4086AW	ISL6144IV-T	ISL6700IBZ-T
HIP4081AIPZ	HIP4086AY	ISL6144IVZA	ISL6700IBZ-TS2568
HIP4081AIR	ISL6140CB	ISL6144IVZA-T	ISL6700IR
HIP4081AIREPR5308	ISL6140CB-T	ISL6144IVZA-TS2490	ISL6700IR-T
HIP4081AIREP-TR5308	ISL6140CBZ	ISL6144IVZA-TS2568	ISL6700IRZ
HIP4081AIR-T	ISL6140CBZ-T	ISL6150CB	ISL6700IRZ-T
HIP4081AIY	ISL6140IB	ISL6150CB-T	ISL6700IW
HIP4082IB	ISL6140IB-T	ISL6150CBZ	ISL6747ARZA
HIP4082IBT	ISL6140IBZ	ISL6150CBZ-T	ISL6747ARZA-T
HIP4082IBTS2366	ISL6140IBZ-T	ISL6150IB	ISL83200CBZ
HIP4082IBTS2366A	ISL6141CB	ISL6150IB-T	ISL83200CBZ-T
HIP4082IBTS2457	ISL6141CB-T	ISL6150IBZ	ISL83202IBZ
HIP4082IBTS2599	ISL6141CBZA	ISL6150IBZ-T	ISL83202IBZT
HIP4082IBZ	ISL6141CBZA-T	ISL6151CB	ISL83202IPZ
HIP4082IBZT	ISL6141IB	ISL6151CB-T	ISL83204AIBZ
HIP4082IP	ISL6141IB-T	ISL6151CBZA	ISL83204AIBZT
HIP4082IPZ	ISL6141IBZA	ISL6151CBZA-T	ISL83204AIPZ
HIP4083AB	ISL6141IBZA-T	ISL6151IB	
HIP4083ABT	ISL6142CB	ISL6151IB-T	

PCN09016 - Qualification Summary - 80V P3/PASIC EPI Process Improvement

Reliability Test	HIP4082IB*	ISL6144*	Comments
High Temperature Operating Life	Qualification Lot - New Process ss = 234 from 3 lots (0, 168, 500, 1000 hrs)	NA	
	Control Lot - Old Process ss = 40 from 1 lot (0, 168, 500, 1000 hrs)		
Product Electrical Characterization	ss =600 from 6 lots 100 per lot , 3 lots new process 100 per lot , 3 lots old process Tested over temperature (Room, High, Low) Evaluation by statistical distribution, not delta, match or exceed existing performance.	ss = 60 from 2 lots 30 per lot , 1 lot new process 30 per lot , 1 lot old process Tested over temperature (Room, High, Low) Evaluation by statistical distribution, not delta, match or exceed existing performance.	Product characterization was performed and the parts manufactured with the new EPI process matches the performance of the existing process.
ESD Characterization	ss = 18 (9 new process, 9 old process) 3 - HBM 3 - CDM 3 - MM	ss = 18 (9 new process, 9 old process) 3 - HBM 3 - CDM 3 - MM	ESD performance of parts with the new EPI process matches the performance of the existing process.
Latch-up Characterization	ss = 12 (6 new process, 6 old process) 2 per lot , 3 lots new process 2 per lot , 3 lots old process	ss = 12 (6 new process, 6 old process) 2 per lot , 3 lots new process 2 per lot , 3 lots old process	Latch-up performance of parts with the new EPI process matches the performance of the existing process.